





TEST REPORT

No. I19Z70333-EMC02

for

Samsung Electronics. Co., Ltd.

Mobile phone

Model Name: SM-A015A,SM-A015AZ

FCC ID: ZCASMA015A

with

Hardware Version: REV3.0

Software Version: A015A.001(A015AUCU0ATAC),

A015AZ.001(A015AZUCE0ATA1)

Issued Date: 2020-02-11

Note:

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Test Laboratory:

CTTL-Telecommunication Technology Labs, CAICT

No. 52, Huayuan North Road, Haidian District, Beijing, P. R. China 100191.

Tel:+86(0)10-62304633-2512, Fax:+86(0)10-62304633-2504

Email: cttl_terminals@caict.ac.cn, website: www.caict.ac.cn





REPORT HISTORY

Report Number	Revision	Description	Issue Date	
I19Z70333-EMC02	Rev.0	1 st edition	2020-02-11	

Note: the latest revision of the test report supersedes all previous version.





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1. Test Laboratory

1.1. Introduction & Accreditation

Telecommunication Technology Labs, CAICT is an ISO/IEC 17025:2005 accredited test laboratory under NATIONAL VOLUNTARY LABORATORY ACCREDITATION PROGRAM (NVLAP) with lab code 600118-0, and is also an FCC accredited test laboratory (CN5017), and ISED accredited test laboratory (CN0066). The detail accreditation scope can be found on NVLAP website.

2. Test Laboratory

2.1. Testing Location

CTTL(huayuan North Road)

Address: No. 52, Huayuan North Road, Haidian District, Beijing,

P. R. China100191

2.2. <u>Testing Environment</u>

Normal Temperature: 15-35° C Relative Humidity: 20-75%

2.3. Project data

Testing Start Date: 2019-11-11
Testing End Date: 2019-12-16

2.4. Signature

Wang Junqing

(Prepared this test report)

张

Zhang Ying

(Reviewed this test report)

Liu Baodian

Deputy Director of the laboratory

(Approved this test report)





3. Client Information

3.1. Applicant Information

Company Name: Samsung Electronics. Co., Ltd.

R5, A Tower 22 Floor A-1,(Maetan dong)

Address: 129,Samsung-ro,Yeongtong-gu, Suwon-Si, Gyeonggi-do 16677,

Korea

City: /
Postal Code: /

Country: Korea

Telephone: +82-10-4376-0326

Fax: /

3.2. Manufacturer Information

Company Name: Samsung Electronics. Co., Ltd.

R5, A Tower 22 Floor A-1,(Maetan dong)

Address: 129,Samsung-ro,Yeongtong-gu, Suwon-Si, Gyeonggi-do 16677,

Korea

City: /
Postal Code: /

Country: Korea

Telephone: +82-10-4376-0326

Fax: /





4. Equipment Under Test (EUT) and Ancillary Equipment (AE)

4.1. About EUT

Description Mobile phone

Model Name SM-A015A,SM-A015AZ

FCC ID ZCASMA015A

Power Supply 3.85V

Note: Components list, please refer to documents of the manufacturer; it is also included in the original test record of CTTL,Telecommunication Technology Labs, CAICT.

4.2. Internal Identification of EUT used during the test

EUT ID*	SN or IMEI	HW Version	SW Version
EUT1	/	/	/
EUT3	351766110007292	DE//3 0	A015A.001(A015AUCU0ATAC),
	331700110007292	NL V 3.0	A015AZ.001(A015AZUCE0ATA1)

^{*}EUT ID: is used to identify the test sample in the lab internally.

4.3. Internal Identification of AE used during the test

AE ID*	Description	SN	Remarks		
AE1	Battery	/	/		
AE2	Battery	/	/		
AE3	Charger	/	/		
AE4	Charger	/	/		
AE5	Charger	/	/		
AE6	USB Cable	/	/		
AE7	Headset	/	/		
AE10	OTG Cable	/	/		
AE1					
Model		QL1695			
Manufacturer		Ningde Am	Ningde Amperex Technology Limited		
Capacitance		/			
Nominal voltage		3.85 V			
AE2					
Model		QL1695			
Manufa	cturer	SCUD(Fujia	an) Electronics Co., Ltd.		
Capacit	ance	/			
Nomina	l voltage	3.85 V			
AE3					
Model		EP-TA50JV	VE		
Manufa	cturer	DongYang	E&P Inc.		
Length	of cable	/			
AE4					
Model		EP-TA50JV	VE		

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Manufacturer HAEM Co.,Ltd

Length of cable

AE5

Model EP-TA50JWE Manufacturer RF Tech

Length of cable

AE6

Model EP-DR140AWE

Manufacturer LUXSHARE-ICT (VIETNAM) LIMITED

Length of cable

AE7

Model EHS61ASFWE

Manufacturer DONGGUAN YOUNGBO ELECTRONICS CO.,LTD

Length of cable /

AE10

Model //
Manufacturer //
Length of cable //

Note: The USB cables are shielded.

4.4. EUT set-ups

EUT set-up No.	Combination of EUT and AE	Remarks
Set.8	EUT1+ AE1/AE2+ AE4+ AE6	Charger
Set.9	EUT3+ AE1/AE2+ AE4+ AE6	Charger

Note: Mobile phone SM-A015A,SM-A015AZ manufactured by Samsung Electronics. Co., Ltd. is a variant model based onSM-A015T1 for conformance test. According to the declaration of changes, adding the tests as follow:

Test Item	Mode	
Radiated Emission	Set.9 LTE band 14	

The other results are cited from the initial model. The report number for initial model is I19Z70327-EMC02.

^{*}AE ID: is used to identify the test sample in the lab internally.





5. Reference Documents

5.1. Reference Documents for testing

The following documents listed in this section are referred for testing.

Reference	Title	Version
FCC Part 15, Subpart B	Radio frequency devices - Unintentional Radiators	2016
ANSI C63.4	American National Standard for	2014
	Methods of Measurement of Radio-	
	Noise Emissions from Low-Voltage	
	Electrical and Electronic Equipment	
	in the Range of 9 kHz to 40 GHz	

Note: The test methods have no deviation with standards.





6. LABORATORY ENVIRONMENT

Semi-anechoic chamber SAC-1 (23 meters \times 17meters \times 10meters) did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 35 °C		
Relative humidity	Min. = 15 %, Max. = 75 %		
Shielding effectiveness	0.014MHz-1MHz, >60dB;		
	1MHz - 1000MHz, >90dB.		
Electrical insulation	> 2 MΩ		
Ground system resistance	< 4 Ω		
Normalised site attenuation (NSA)	< ±4 dB, 10 m distance		
Site voltage standing-wave ratio (S _{VSWR})	Between 0 and 6 dB, from 1GHz to 6GHz		
Uniformity of field strength	Between 0 and 6 dB, from 80 to 3000 MHz		

Shielded room did not exceed following limits along the EMC testing:

Temperature	Min. = 15 °C, Max. = 35 °C		
Relative humidity	Min. = 20 %, Max. = 75 %		
Shielding effectiveness	0.014MHz-1MHz, >60dB;		
	1MHz-1000MHz, >90dB.		
Electrical insulation	> 2 MΩ		
Ground system resistance	< 4 Ω		





7. SUMMARY OF TEST RESULTS

Abbreviations used in this clause:		
	Р	Pass
Verdict Column	NA	Not applicable
	F	Fail

Items	Test Name	Clause in FCC rules	Section in this report Verdict		Test Location
1	Radiated Emission	15.109(a)	B.1	Р	CTTL(huayuan North Road)





8. Test Equipments Utilized

NO.	Description	TYPE	SERIES NUMBER	MANUFACTURE	CAL DUE DATE	CALIBRATI ON INTERVAL
1	Test Receiver	ESU26	100235	R&S	2020-03-01	1 Year
2	Universal Radio Communication Tester	CMW500	150344	R&S	2020-11-17	1 year
3	Universal Radio Communication Tester	CMW500	116588	R&S	2020-12-26	1 year
4	EMI Antenna	VULB 9163	9163-1222	Schwarzbeck	2020-03-14	1 year





ANNEX A: MEASUREMENT RESULTS

A.1 Radiated Emission

Reference

FCC: CFR Part 15.109(a).

A.1.1 Method of measurement

The field strength of radiated emissions from the unintentional radiator at distances of 10 meters(for 30MHz-1GHz). Tested in accordance with the procedures of ANSI C63.4 – 2014, section 8.3.

The EUT was placed on a non-conductive table. The measurement antenna was placed at a distance of 3/10 meters from the EUT. During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations.

A.1.2 EUT Operating Mode

The MS is operating in the charging mode and transmitter receiver mode.

A.1.3 Measurement Limit

Frequency range	Field strength limit (µV/m)						
(MHz)	Quasi-peak	Peak					
30-88	100						
88-216	150						
216-960	200						
960-1000	500						
>1000		500	5000				

Note: the above limit is for 3 meters test distance. 10 meters' limit is got by converting.

A.1.4 Test Condition

	Frequency range (MHz)	RBW/VBW	Sweep Time (s)	Detector
Ī	30-1000	120kHz (IF Bandwidth)	5	Peak/Quasi-peak





A.1.5 Measurement Results

A "reference path loss" is established and the A_{Rpl} is the attenuation of "reference path loss". It includes the antenna factor of receive antenna and the path loss.

The measurement results are obtained as described below:

Result = $P_{Mea} + A_{Rpl} = P_{Mea} + G_A + G_{PL}$

Where

G_A: Antenna factor of receive antenna

G_{PL}: Path Loss

P_{Mea}: Measurement result on receiver.

Measurement uncertainty (worst case): U = 5.44 dB, k=2.

Charging Mode, GSM850MHz, idle, channel 128

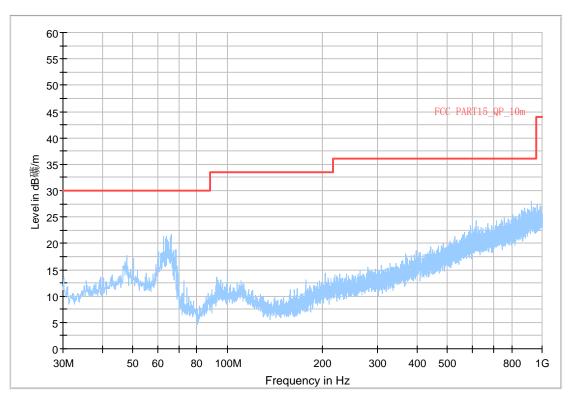


Fig A.1 Radiated Emission from 30MHz to 1GHz, GSM850MHz, idle, channel 128





Charging Mode, GSM850MHz, idle, channel 190

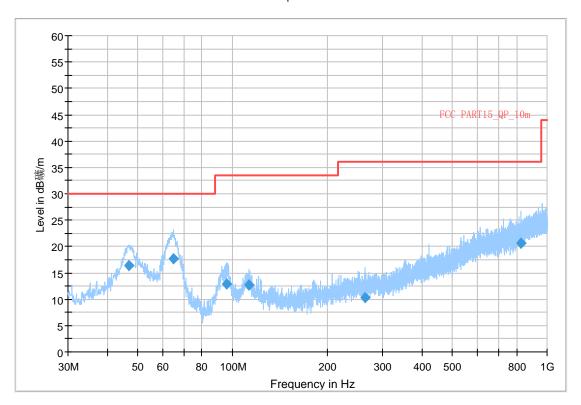


Fig A.2 Radiated Emission from 30MHz to 1GHz, GSM850MHz, idle, channel 190 Final_Result

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
46.846000	16.37	30.00	13.63	1000.0	120.000	125.0	V	263.0
65.077000	17.71	30.00	12.29	1000.0	120.000	104.0	٧	183.0
95.905000	12.80	33.50	20.72	1000.0	120.000	179.0	٧	261.0
112.662000	12.62	33.50	20.90	1000.0	120.000	125.0	٧	255.0
263.271000	10.28	36.00	25.74	1000.0	120.000	125.0	٧	90.0
824.675000	20.69	36.00	15.33	1000.0	120.000	125.0	٧	-30.0





Charging Mode, GSM850MHz, idle, channel 251

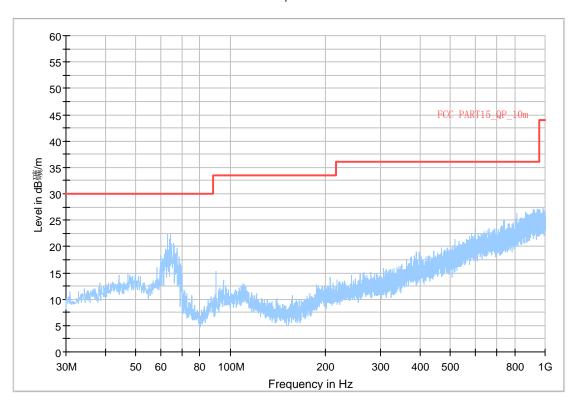


Fig A.3 Radiated Emission from 30MHz to 1GHz, GSM850MHz, idle, channel 251





Charging Mode, WCDMA850MHz, idle, channel 4132

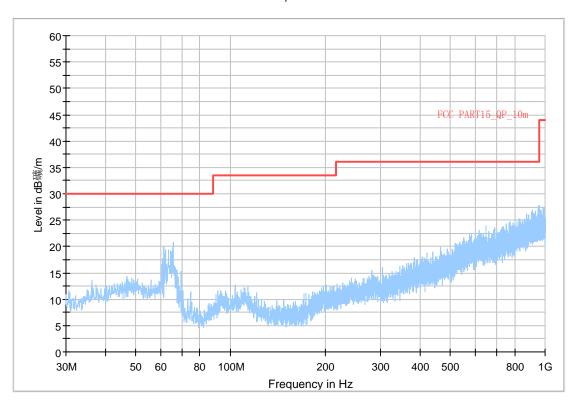


Fig A.4 Radiated Emission from 30MHz to 1GHz, WCDMA850MHz, idle, channel 4132





Charging Mode, WCDMA850MHz, idle, channel 4183

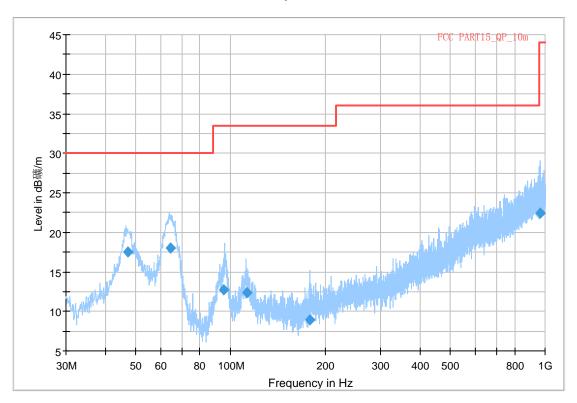


Fig A.5 Radiated Emission from 30MHz to 1GHz, WCDMA850MHz, idle, channel 4183

Final_Result

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
47.261000	17.47	30.00	12.53	1000.0	120.000	111.0	V	-5.0
64.333000	18.04	30.00	11.96	1000.0	120.000	225.0	٧	-12.0
95.152000	12.68	33.50	20.84	1000.0	120.000	102.0	٧	287.0
112.893000	12.38	33.50	21.14	1000.0	120.000	125.0	٧	265.0
178.267000	8.87	33.50	24.65	1000.0	120.000	119.0	٧	8.0
962.794000	22.43	44.00	21.55	1000.0	120.000	325.0	٧	168.0





Charging Mode, WCDMA850MHz, idle, channel 4233

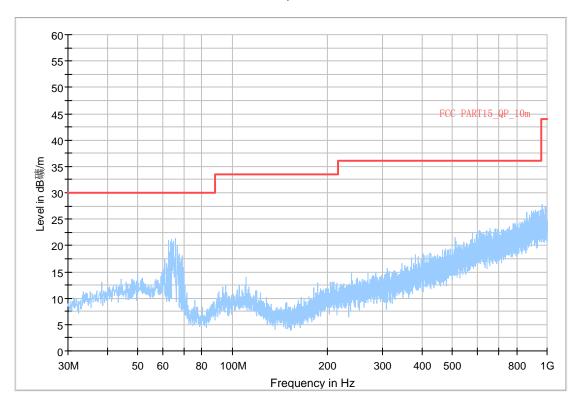


Fig A.6 Radiated Emission from 30MHz to 1GHz, WCDMA850MHz, idle, channel 4233





Charging Mode, LTE band 5, idle, channel 20407

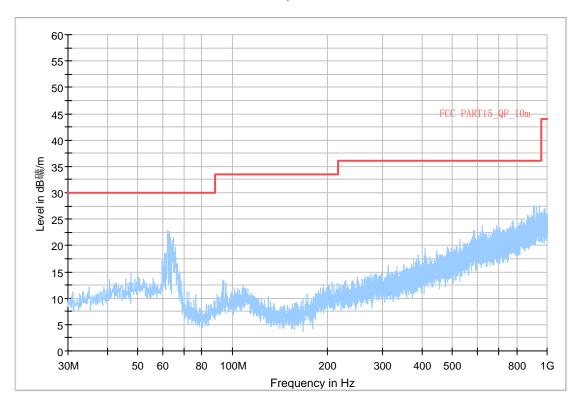


Fig A.7 Radiated Emission from 30MHz to 1GHz, LTE band 5, idle, channel 20407





Charging Mode, LTE band 5, idle, channel 20525

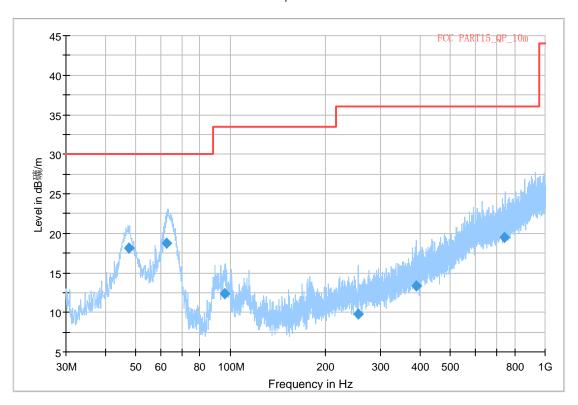


Fig A.8 Radiated Emission from 30MHz to 1GHz, LTE band 5, idle, channel 20525 Final_Result

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
47.428000	18.13	30.00	11.87	1000.0	120.000	102.0	V	151.0
62.814000	18.72	30.00	11.28	1000.0	120.000	102.0	٧	151.0
95.734000	12.35	33.50	21.17	1000.0	120.000	125.0	٧	-30.0
255.534000	9.81	36.00	26.21	1000.0	120.000	288.0	٧	30.0
390.240000	13.35	36.00	22.67	1000.0	120.000	282.0	٧	107.0
745.029000	19.44	36.00	16.58	1000.0	120.000	125.0	V	30.0





Charging Mode, LTE band 5, idle, channel 20643

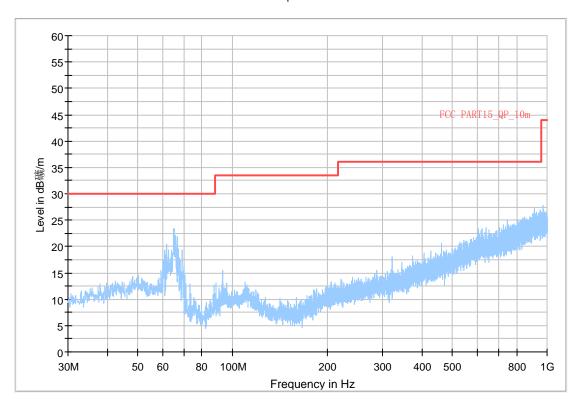


Fig A.9 Radiated Emission from 30MHz to 1GHz, LTE band 5, idle, channel 20643





Charging Mode, LTE band 14, idle, channel 23305

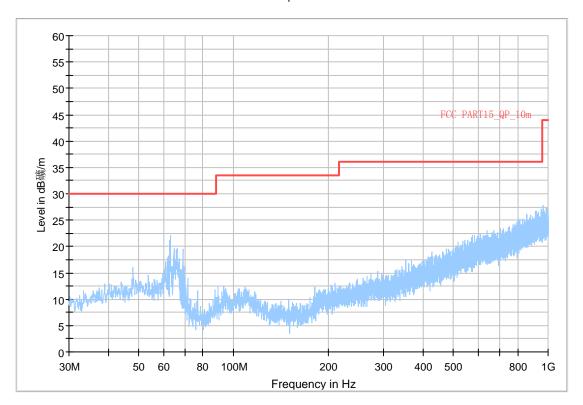


Fig A.10 Radiated Emission from 30MHz to 1GHz, LTE band 14, idle, channel 23305





Charging Mode, LTE band 14, idle, channel 23330

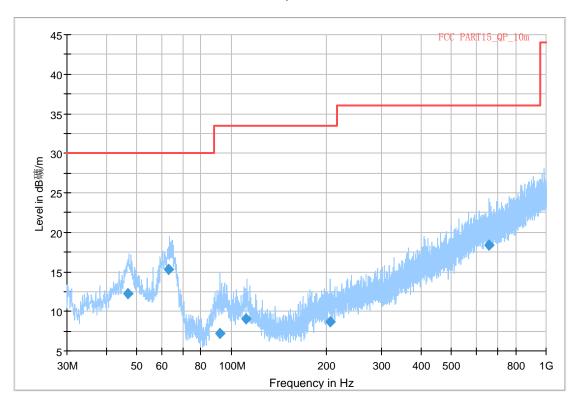


Fig A.11 Radiated Emission from 30MHz to 1GHz, LTE band 14, idle, channel 23330 Final_Result

Frequency	QuasiPeak	Limit	Margin	Meas.	Bandwidth	Height	Pol	Azimuth
(MHz)	(dBuV/m)	(dBuV/m)	(dB)	Time	(kHz)	(cm)		(deg)
				(ms)				
46.989000	12.22	30.00	17.78	1000.0	120.000	201.0	V	90.0
63.059000	15.31	30.00	14.69	1000.0	120.000	225.0	٧	72.0
91.637000	7.20	33.50	26.32	1000.0	120.000	201.0	٧	61.0
111.365000	9.01	33.50	24.51	1000.0	120.000	303.0	٧	273.0
206.443000	8.68	33.50	24.84	1000.0	120.000	189.0	٧	30.0
660.089000	18.39	36.00	17.63	1000.0	120.000	125.0	V	-30.0





Charging Mode, LTE band 14, idle, channel 23355

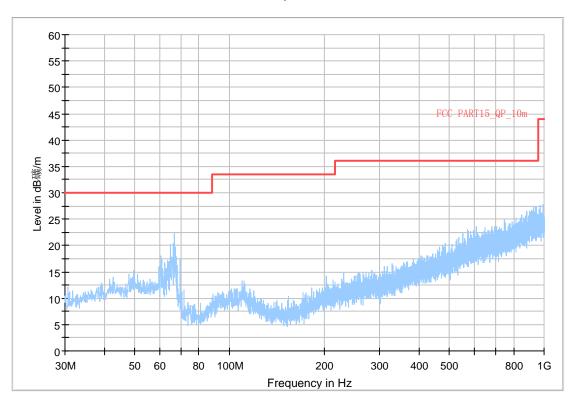


Fig A.12 Radiated Emission from 30MHz to 1GHz, LTE band 14, idle, channel 23355





ANNEX B: PERSONS INVOLVED IN THIS TESTING

Test Item	Test Software and Version	Software Vendor	Test operator
Radiated Emission	EMC32 V9.01.00	R&S	Yan Hanchen

END OF REPORT